

Fall 10-5-2015

Orientation-depedent mechanical behaviour of electrodeposited copper with nanoscale twins

Maxime Mieszala

EMPA, maxime.mieszala@empa.ch

Guillonneau Gayrlord

Ecole Centrale de Lyon

Jeffrey Wheeler

EMPA

Rejin Raghavan

Max Planck Institut fur Eisenforschung

Madoka Hasegawa

EMPA

See next page for additional authors

Follow this and additional works at: http://dc.engconfintl.org/nanomechtest_v



Part of the [Materials Science and Engineering Commons](#)

Recommended Citation

1 M. Dao, L. Lu, Y.F. Shen, and S. Suresh, *Acta Mater.* 54, 5421 (2006). 2 M. Hasegawa, M. Mieszala, Y. Zhang, R. Erni, J. Michler, and L. Philippe, *Electrochem. Acta* (2015), Accepted for publication, doi:10.1016/j.electacta.2015.08.022

This Abstract is brought to you for free and open access by the Proceedings at ECI Digital Archives. It has been accepted for inclusion in Nanomechanical Testing in Materials Research and Development V by an authorized administrator of ECI Digital Archives. For more information, please contact franco@bepress.com.

Authors

Maxime Mieszala, Guillonneau Gaylord, Jeffrey Wheeler, Rejin Raghavan, Madoka Hasegawa, Johann Michler, and Laetitia Phillippe

ORIENTATION-DEPENDENT MECHANICAL BEHAVIOUR OF ELECTRODEPOSITED COPPER WITH NANOSCALE TWINS

Maxime Mieszala, Empa – Swiss Federal Laboratories for Materials Science and Technology, Switzerland
maxime.mieszala@empa.ch

Guillonneau Gaylord, Ecole Centrale de Lyon, Université de Lyon, Laboratoire de Tribologie et Dynamique des Systèmes, UMR 5513 CNRS/ECL/ENISE, France

Jeffrey M. Wheeler, Empa – Swiss Federal Laboratories for Materials Science and Technology, Switzerland,
ETH Zurich, Switzerland

Rejin Raghavan, Max-Planck-Institut für Eisenforschung GmbH, Düsseldorf, Germany

Madoka Hasegawa, Empa – Swiss Federal Laboratories for Materials Science and Technology, Switzerland

Stefano Mischler, Ecole Polytechnique Fédérale de Lausanne (EPFL), Switzerland

Johann Michler, Empa – Swiss Federal Laboratories for Materials Science and Technology, Switzerland

Laetitia Philippe, Empa – Swiss Federal Laboratories for Materials Science and Technology, Switzerland

Key Words: twin boundary engineering, Nanotwinned Cu, microcompression

The electrodeposition of copper is an important technology for the fabrication of micro-components and interconnects. In contrast to nanocrystalline copper, nanotwinned Cu (nt-Cu) exhibits remarkable strength, ductility and electrical conductivity¹. Our recent work² reported the possibility to deposit copper samples with highly-oriented nanoscale twins by pulse electrodeposition. The twin orientation was altered from horizontal to vertical by changing the applied potential and the twin spacing was controlled with pulse-off time.

In this poster, we report the orientation-dependent mechanical properties of electrodeposited copper with nanoscale twins confined within micron-sized columnar grains. The strength and strain rate sensitivity are investigated with respect to the twin orientation by micro-pillar compression. A strong anisotropy is observed between both orientations. A higher strength and strain rate sensitivity is measured for micro-pillars with horizontal twins when compared to vertical twins. Mechanisms responsible for this effect are explored through post-deformation SEM and FIB imaging. The plastic anisotropy was related to the change in critical resolved shear stress in twinned slip system. The experimental work shows the possibility to tailor the mechanical properties of nt-Cu by grain boundary engineering.

¹ M. Dao, L. Lu, Y.F. Shen, and S. Suresh, *Acta Mater.* **54**, 5421 (2006).

² M. Hasegawa, M. Mieszala, Y. Zhang, R. Erni, J. Michler, and L. Philippe, *Electrochem. Acta* (2015), Accepted for publication, [doi:10.1016/j.electacta.2015.08.022](https://doi.org/10.1016/j.electacta.2015.08.022).

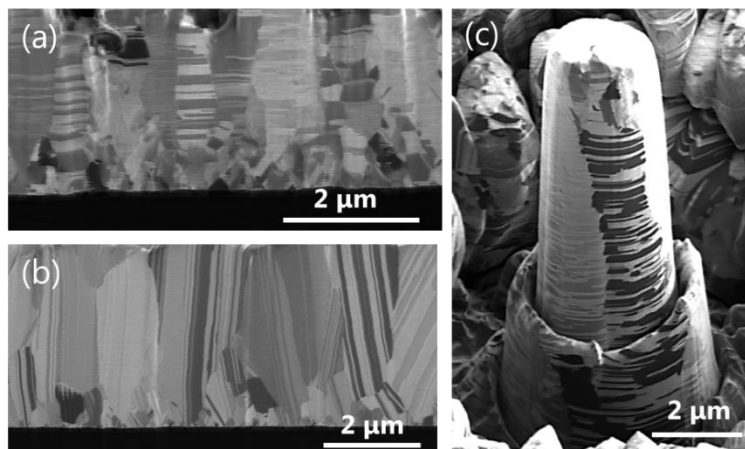


Figure 1 – Cross-section images (a) (111)-textured and (b) (112)-textured copper films. (c) FIB micrograph of a micropillar.